

BLF8G27LS-100V; BLF8G27LS-100GV

Power LDMOS transistor

Rev. 4 — 26 September 2013

Product data sheet

1. Product profile

1.1 General description

100 W LDMOS power transistor with improved video bandwidth for base station applications at frequencies from 2500 MHz to 2700 MHz.

Table 1. Typical performance

Typical RF performance at $T_{case} = 25\text{ °C}$ in a common source class-AB production test circuit.

| Test signal | f (MHz) | I_{Dq} (mA) | V_{DS} (V) | $P_{L(AV)}$ (W) | G_p (dB) | η_D (%) | ACPR _{5M} (dBc) |
|------------------|--------------|------------------|-----------------|--------------------|---------------|-----------------|-----------------------------|
| 2-carrier W-CDMA | 2500 to 2700 | 900 | 28 | 25 | 17 | 28 | -32 [1] |

[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF per carrier; 5 MHz carrier spacing.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Decoupling leads to enable improved video bandwidth (110 MHz typical)
- Designed for broadband operation (2500 MHz to 2700 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

- RF power amplifiers for base stations and multi carrier applications in the 2500 MHz to 2700 MHz frequency range



2. Pinning information

Table 2. Pinning

| Pin | Description | Simplified outline | Graphic symbol |
|-----------------------------------|----------------------------|--------------------|----------------|
| BLF8G27LS-100V (SOT1244B) | | | |
| 1 | drain | | aaa-003619 |
| 2 | gate | | |
| 3 | source [1] | | |
| 4 | decoupling lead | | |
| 5 | decoupling lead | | |
| 6 | n.c. | | |
| 7 | n.c. | | |
| BLF8G27LS-100GV (SOT1244C) | | | |
| 1 | drain | | aaa-003619 |
| 2 | gate | | |
| 3 | source [1] | | |
| 4 | decoupling lead | | |
| 5 | decoupling lead | | |
| 6 | n.c. | | |
| 7 | n.c. | | |

[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

| Type number | Package | | |
|-----------------|---------|--|----------|
| | Name | Description | Version |
| BLF8G27LS-100V | - | earless flanged ceramic package; 6 leads | SOT1244B |
| BLF8G27LS-100GV | - | earless flanged ceramic package; 6 leads | SOT1244C |

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

| Symbol | Parameter | Conditions | Min | Max | Unit |
|-----------|----------------------|------------|------|------|------|
| V_{DS} | drain-source voltage | | - | 65 | V |
| V_{GS} | gate-source voltage | | -0.5 | +13 | V |
| T_{stg} | storage temperature | | -65 | +150 | °C |
| T_j | junction temperature | | - | 225 | °C |

5. Thermal characteristics

Table 5. Thermal characteristics

| Symbol | Parameter | Conditions | Typ | Unit |
|---------------|--|--|-------|------|
| $R_{th(j-c)}$ | thermal resistance from junction to case | $T_{case} = 80\text{ °C}; P_L = 48\text{ W}$ | 0.292 | K/W |

6. Characteristics

Table 6. DC characteristics

$T_j = 25\text{ °C}$ unless otherwise specified.

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|---------------|----------------------------------|---|-----|------|-----|---------------|
| $V_{(BR)DSS}$ | drain-source breakdown voltage | $V_{GS} = 0\text{ V}; I_D = 1\text{ mA}$ | 65 | - | - | V |
| $V_{GS(th)}$ | gate-source threshold voltage | $V_{DS} = 10\text{ V}; I_D = 153\text{ mA}$ | 1.5 | 1.9 | 2.3 | V |
| I_{DSS} | drain leakage current | $V_{GS} = 0\text{ V}; V_{DS} = 28\text{ V}$ | - | - | 4.2 | μA |
| I_{DSX} | drain cut-off current | $V_{GS} = V_{GS(th)} + 3.75\text{ V}; V_{DS} = 10\text{ V}$ | - | 29 | - | A |
| I_{GSS} | gate leakage current | $V_{GS} = 11\text{ V}; V_{DS} = 0\text{ V}$ | - | - | 420 | nA |
| g_{fs} | forward transconductance | $V_{DS} = 10\text{ V}; I_D = 153\text{ mA}$ | - | 1.27 | - | S |
| $R_{DS(on)}$ | drain-source on-state resistance | $V_{GS} = V_{GS(th)} + 3.75\text{ V}; I_D = 5.35\text{ A}$ | - | 0.1 | - | Ω |

Table 7. RF characteristics

Test signal: 2-carrier W-CDMA, 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on the CCDF; $f_1 = 2502.5\text{ MHz}; f_2 = 2507.5\text{ MHz}; f_3 = 2692.5\text{ MHz}; f_4 = 2697.5\text{ MHz};$
RF performance at $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}; T_{case} = 25\text{ °C};$ unless otherwise specified; in a class-AB production test circuit.

| Symbol | Parameter | Conditions | Min | Typ | Max | Unit |
|-------------|--------------------------------------|---------------------------|------|-----|-----|------|
| G_p | power gain | $P_{L(AV)} = 25\text{ W}$ | 15.8 | 17 | - | dB |
| η_D | drain efficiency | $P_{L(AV)} = 25\text{ W}$ | 25 | 28 | - | % |
| RL_{in} | input return loss | $P_{L(AV)} = 25\text{ W}$ | - | -10 | - | dB |
| $ACPR_{5M}$ | adjacent channel power ratio (5 MHz) | $P_{L(AV)} = 25\text{ W}$ | - | -32 | -26 | dBc |

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G27LS-100V and BLF8G27LS-100GV are capable of withstanding a load mismatch corresponding to $V_{SWR} = 10 : 1$ through all phases under the following conditions: $V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}; P_L = 100\text{ W}; f = 2500\text{ MHz}.$

7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data; $I_{Dq} = 900\text{ mA}$; $V_{DS} = 28\text{ V}$ (main transistor).

| f (MHz) | Z_S ^[1] (Ω) | Z_L ^[1] (Ω) |
|------------------------|--------------------------------------|--------------------------------------|
| BLF8G27LS-100V | | |
| 2500 | 1.2 – j4.6 | 2.7 – j2.7 |
| 2600 | 2.3 – j5.5 | 2.5 – j2.5 |
| 2700 | 3.8 – j5.2 | 2.1 – j2.6 |
| BLF8G27LS-100GV | | |
| 2500 | 1.7 – j7.4 | 2.4 – j4.9 |
| 2600 | 2.8 – j8.0 | 2.2 – j5.2 |
| 2700 | 4.0 – j7.9 | 2.0 – j5.3 |

[1] Z_S and Z_L defined in [Figure 1](#).

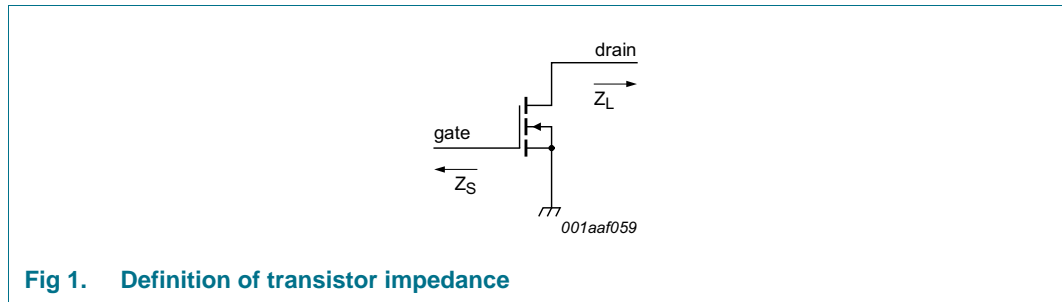


Fig 1. Definition of transistor impedance

7.3 VBW in class-AB operation

The BLF8G27LS-100V and BLF8G27LS-100GV show 110 MHz (typical) video bandwidth in class-AB test circuit in 2.6 GHz band at $V_{DS} = 28\text{ V}$ and $I_{Dq} = 0.9\text{ A}$.

7.4 Test circuit

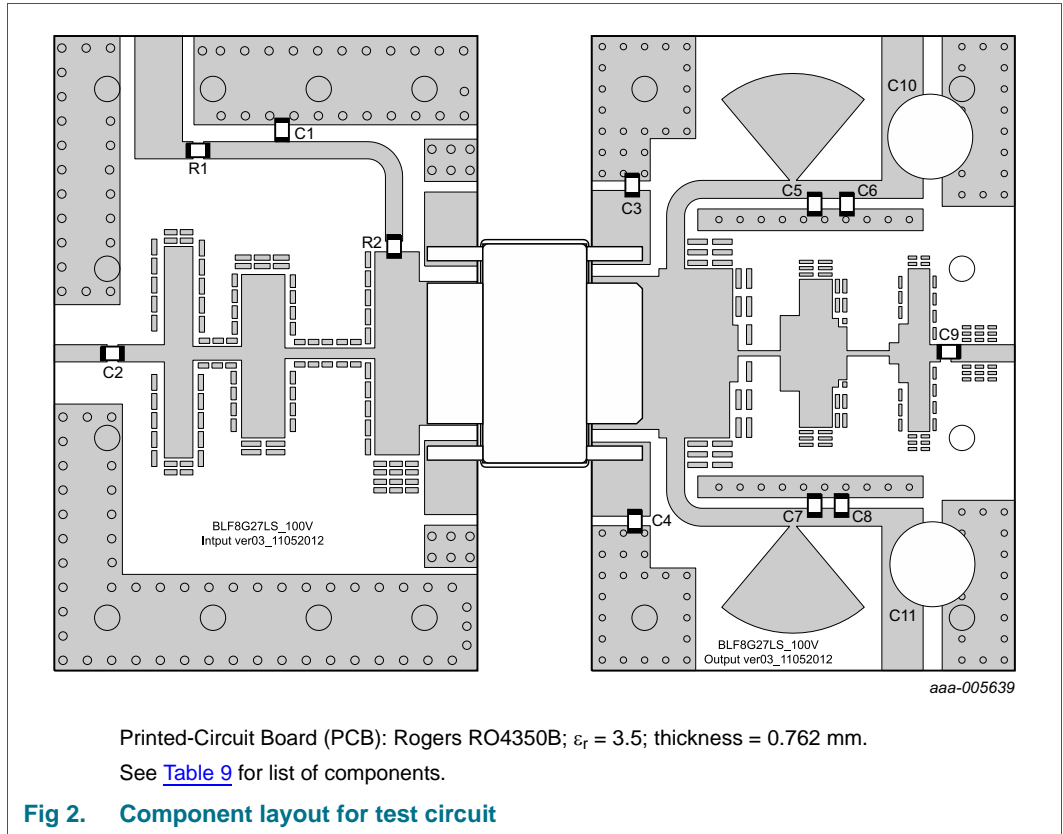


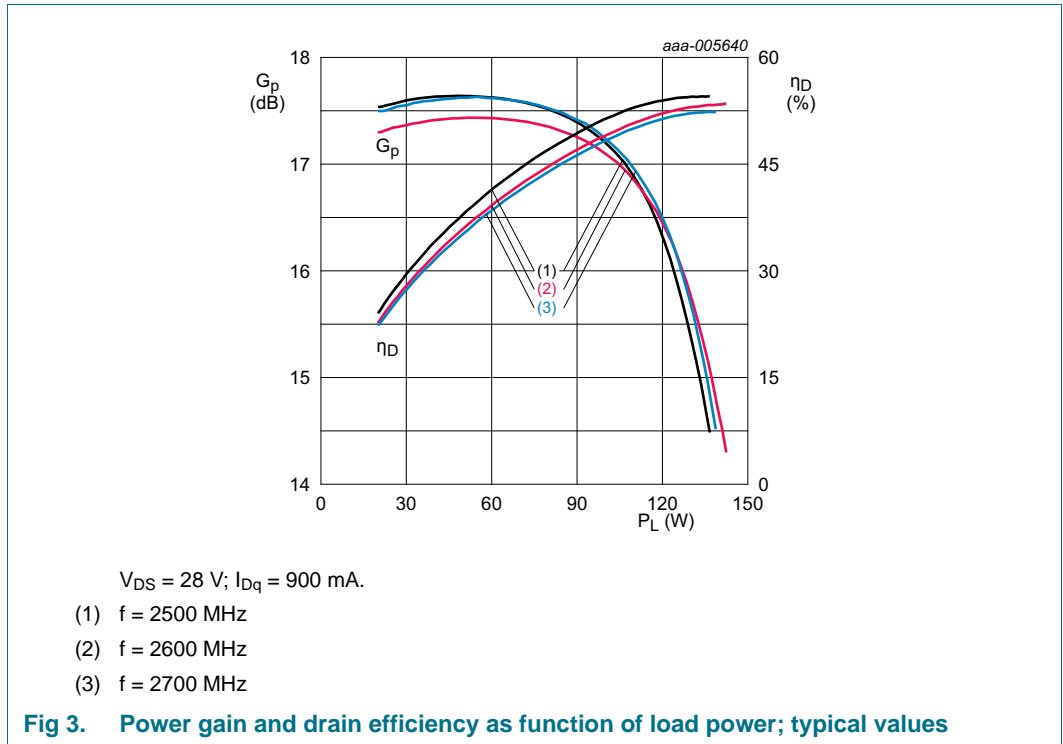
Table 9. List of components

For test circuit, see [Figure 2](#).

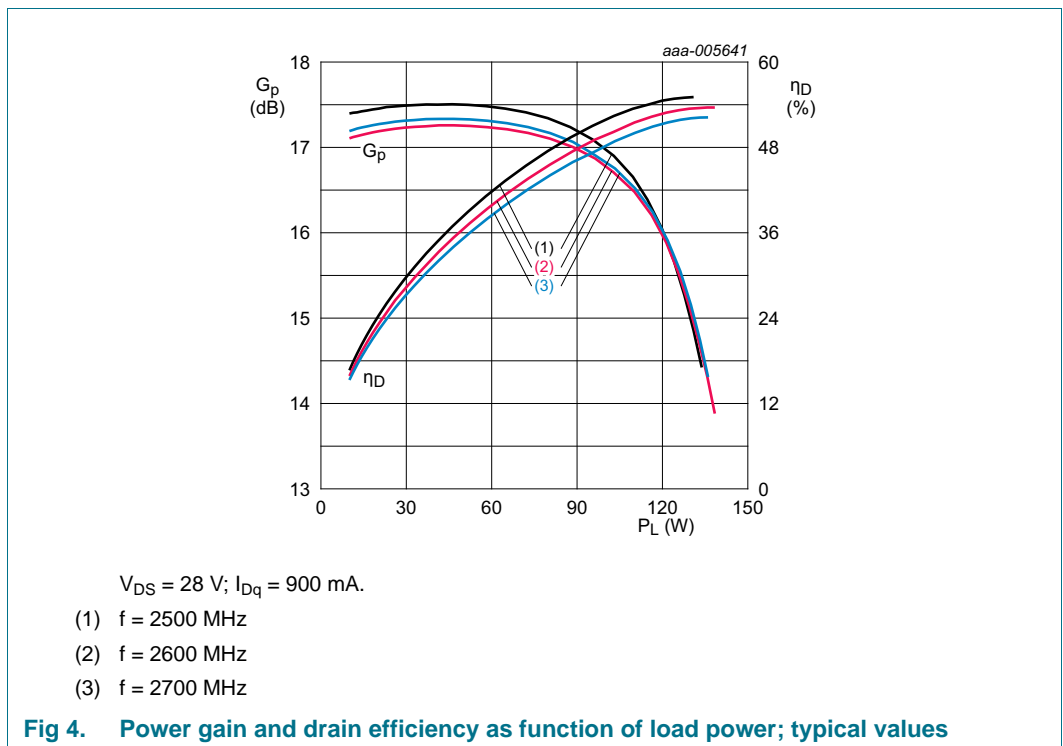
| Component | Description | Value | Remarks |
|----------------|-----------------------------------|---------------------|----------------------|
| C1, C2, C9 | multilayer ceramic chip capacitor | 20 pF | ATC600F |
| C3, C4, C6, C8 | multilayer ceramic chip capacitor | 10 μ F | Murata |
| C5, C7 | multilayer ceramic chip capacitor | 0.1 μ F | Murata |
| C10, C11 | electrolytic capacitor | 1000 μ F, 100 V | |
| R1, R2 | chip resistor | 9.1 Ω | Vishay Dale SMD 0805 |

7.5 Graphical data

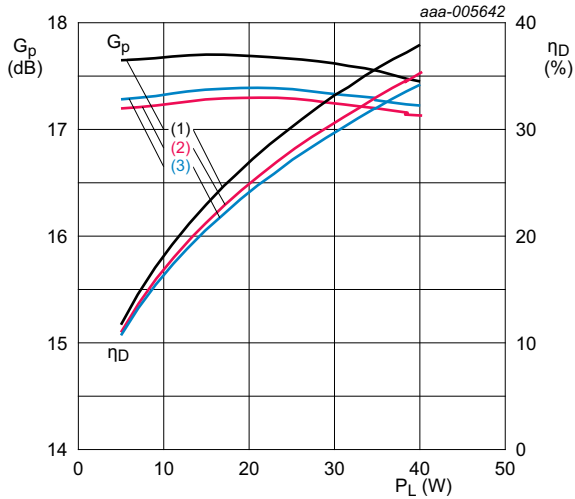
7.5.1 Pulsed CW



7.5.2 1-Tone CW

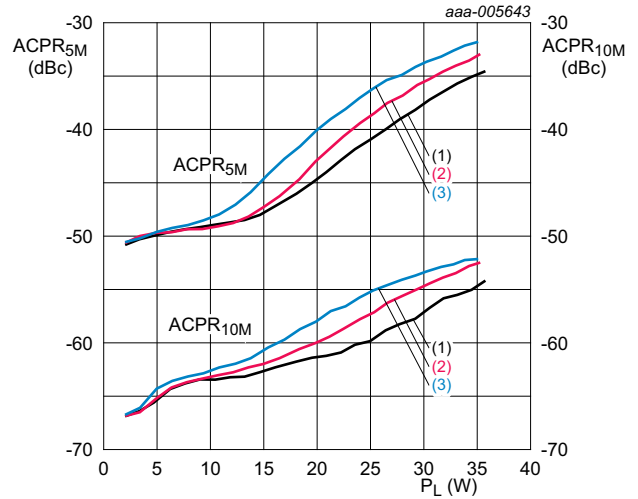


7.5.3 1-Carrier W-CDMA



$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

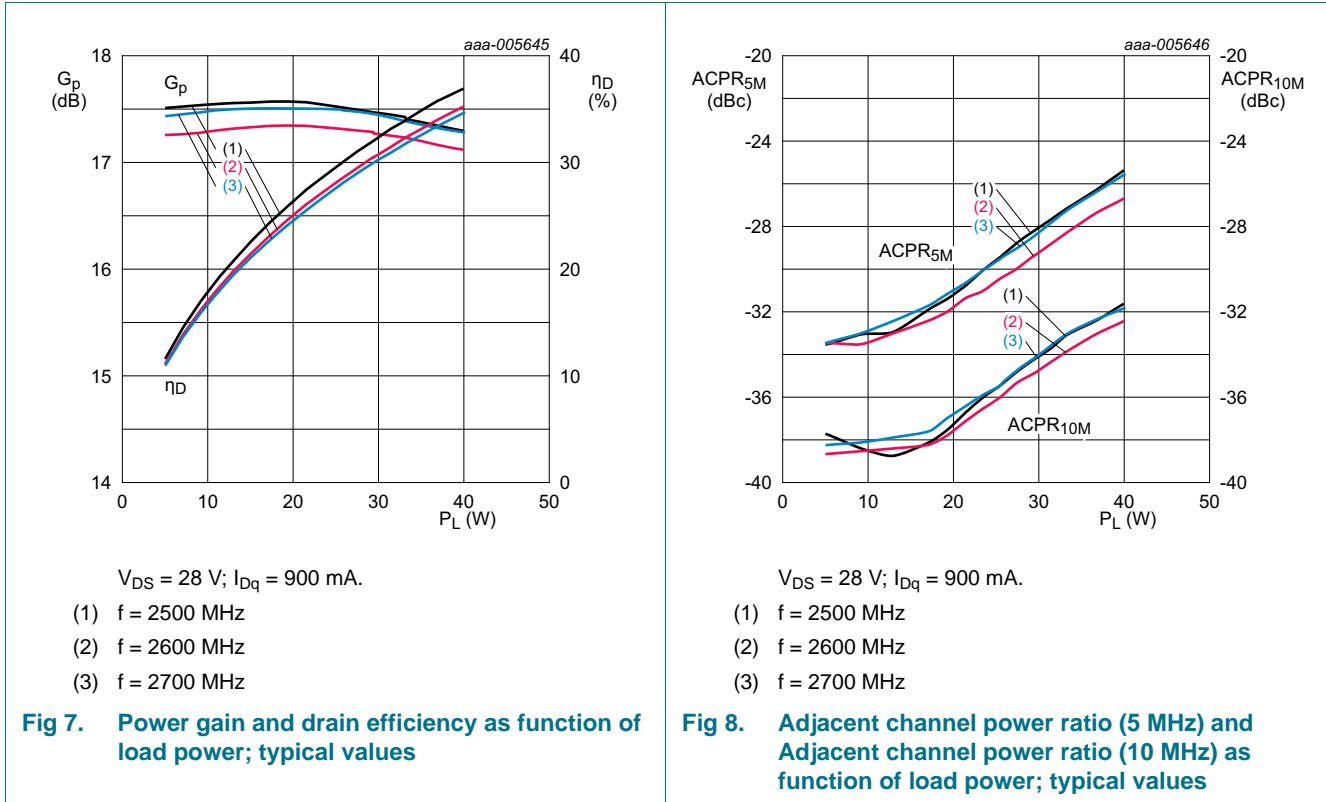
Fig 5. Power gain and drain efficiency as function of load power; typical values



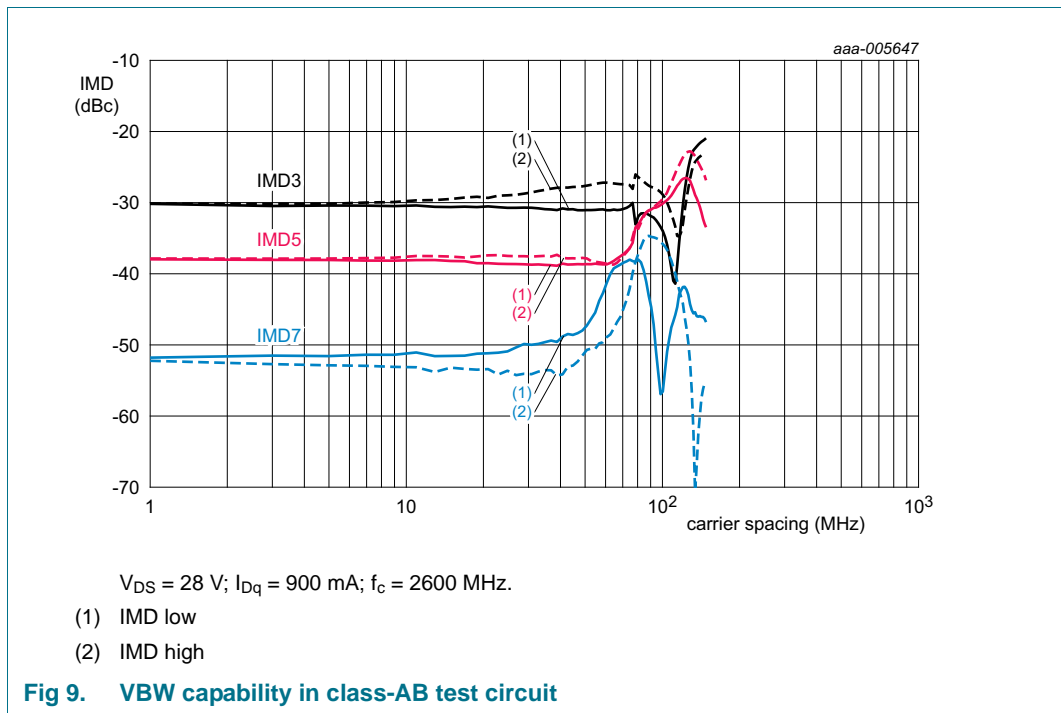
$V_{DS} = 28\text{ V}; I_{Dq} = 900\text{ mA}$.
 (1) $f = 2500\text{ MHz}$
 (2) $f = 2600\text{ MHz}$
 (3) $f = 2700\text{ MHz}$

Fig 6. Adjacent channel power ratio (5 MHz) and Adjacent channel power ratio (10 MHz) as function of load power; typical values

7.5.4 2-Carrier W-CDMA



7.5.5 2-Tone VBW



8. Package outline

Earless flanged ceramic package; 6 leads

SOT1244B

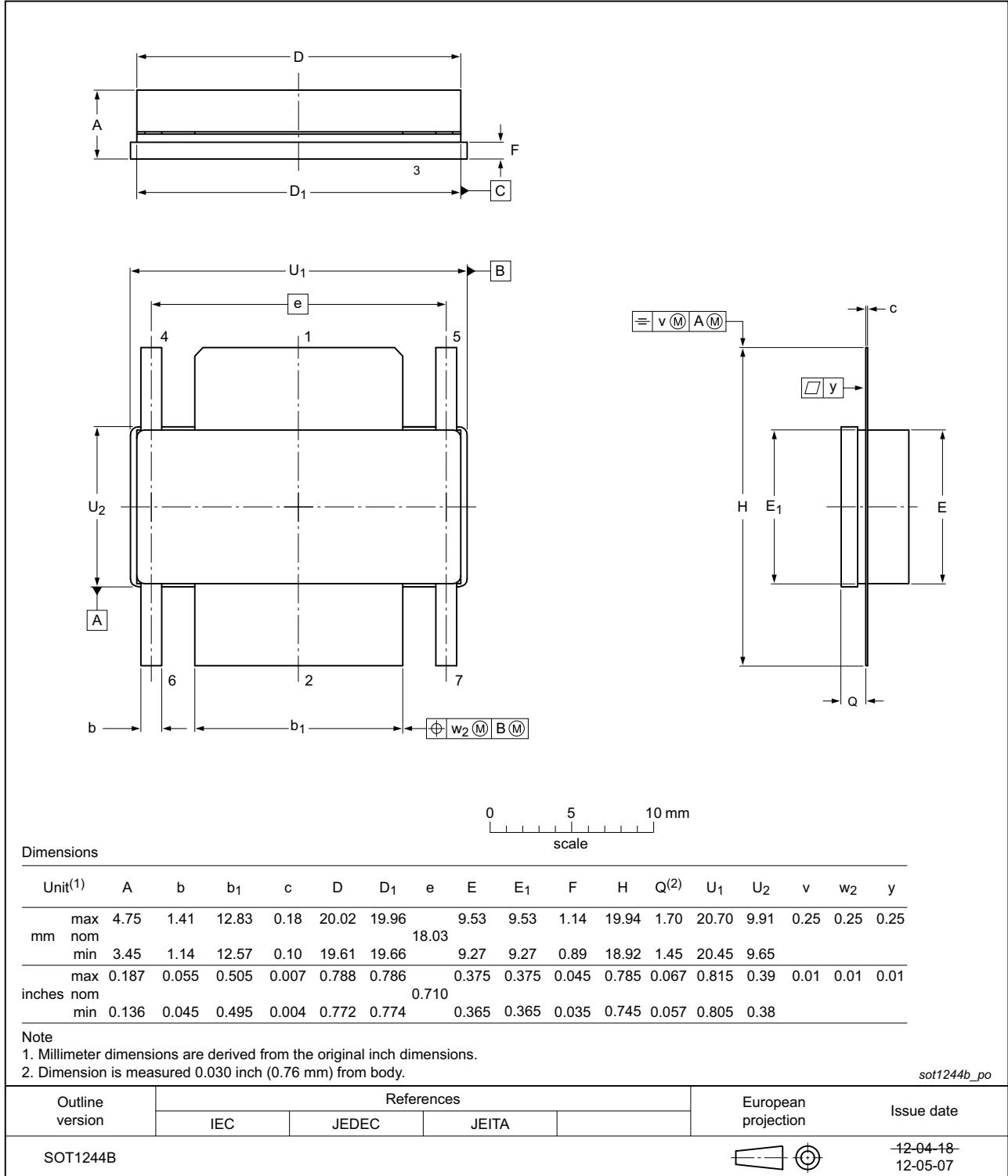


Fig 10. Package outline SOT1244B

Earless flanged ceramic package; 6 leads

SOT1244C

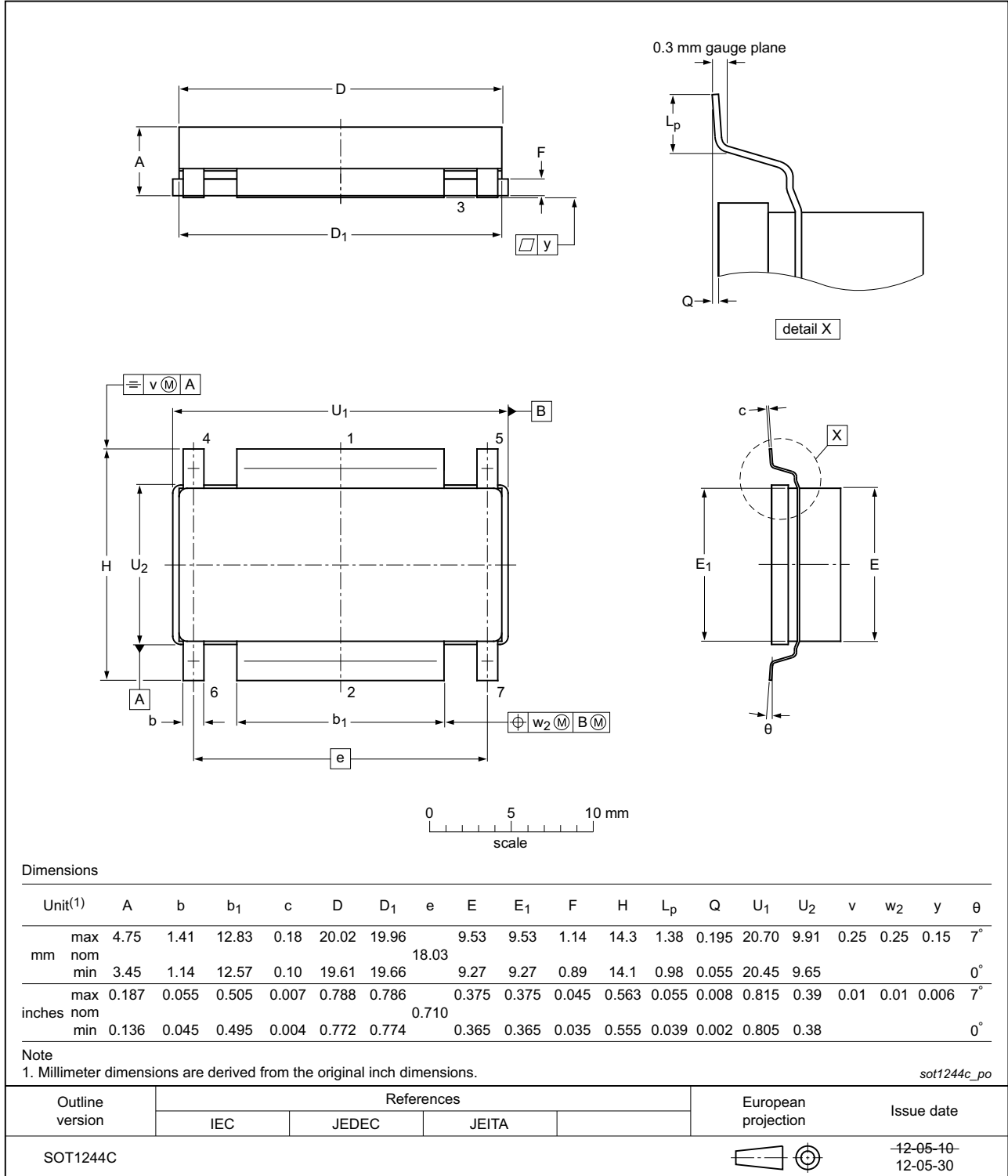


Fig 11. Package outline SOT1244C

9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the *ANSI/ESD S20.20*, *IEC/ST 61340-5*, *JESD625-A* or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

| Acronym | Description |
|---------|--|
| 3GPP | Third Generation Partnership Project |
| CCDF | Complementary Cumulative Distribution Function |
| CW | Continuous Wave |
| DPCH | Dedicated Physical CHannel |
| ESD | ElectroStatic Discharge |
| IMD | InterModulation Distortion |
| LDMOS | Laterally Diffused Metal Oxide Semiconductor |
| PAR | Peak-to-Average Ratio |
| SMD | Surface Mounted Device |
| VBW | Video BandWidth |
| VSWR | Voltage Standing Wave Ratio |
| W-CDMA | Wideband Code Division Multiple Access |

11. Revision history

Table 11. Revision history

| Document ID | Release date | Data sheet status | Change notice | Supersedes |
|-------------------------------|--------------|---|---------------|--------------------|
| BLF8G27LS-100V_27LS-100GV v.4 | 20130926 | Product data sheet | - | BLF8G27LS-100V v.3 |
| Modifications: | | <ul style="list-style-type: none"> This data sheet now describes both the BLF8G27LS-100V and the BLF8G27LS-100GV products. Section 1.2 on page 1: Section has been updated. Section 7.2 on page 4: Section has been updated. | | |
| BLF8G27LS-100V v.3 | 20130129 | Product data sheet | - | BLF8G27LS-100V v.2 |
| BLF8G27LS-100V v.2 | 20121203 | Product data sheet | - | BLF8G27LS-100V v.1 |
| BLF8G27LS-100V v.1 | 20120817 | Objective data sheet | - | - |

12. Legal information

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|-----------------------------------|-------------------------------|---|
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| Product [short] data sheet | Production | This document contains the product specification. |

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